STU5N65M6

N-channel 650 V, 1.15 Ω typ., 4 A MDmesh™ M6 Power MOSFET in an IPAK package

Datasheet - production data

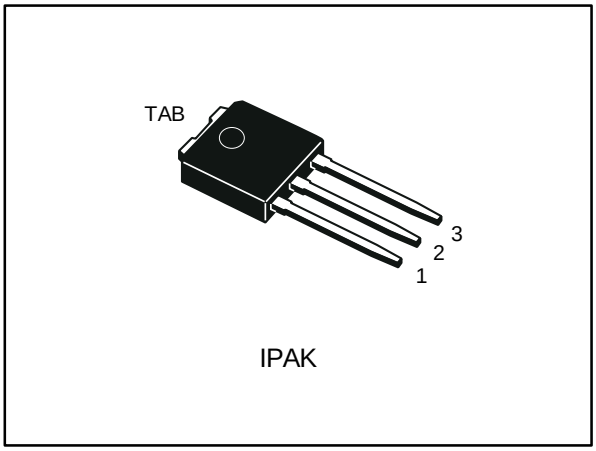
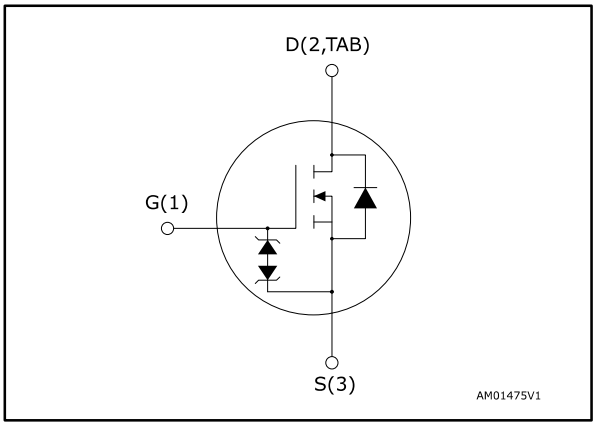


Figure 1: Internal schematic diagram



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STU5N65M6	650 V	1.3 Ω	4 A

- Reduced switching losses
- Lower $R_{DS(on)}$ x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

The new MDmesh™ M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent $R_{DS(on)}$ * area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.

Table 1: Device summary

Order code	Marking	Package	Packing
STU5N65M6	5N65M6	IPAK	Tube

Contents

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at T_C = 25 °C	4	A
I_D	Drain current (continuous) at T_C = 100 °C	2.5	A
I_{DM}(1)	Drain current (pulsed)	16	A
P_{TOT}	Total dissipation at T_C = 25 °C	45	W
dv/dt(2)	Peak diode recovery voltage slope	5	V/ns
dv/dt(3)	MOSFET dv/dt ruggedness	50	
T_J	Operating junction temperature range	-55 to 150	°C
T_{stg}	Storage temperature range		

Notes:

(1)Pulse width limited by safe operating area

(2)$I_{SD} \leq 4$ A, di/dt = 400 A/µs; $V_{DS\ peak} < V_{(BR)DSS}$, V_{DD} = 400 V

(3)$V_{DS} \leq 520$ V

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	2.78	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient	100	

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	1	A
E_{as}	Single pulse avalanche energy (starting T_j=25°C, I_D= I_{AR}, V_{DD}=50 V)	90	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 5: On/off-state

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS}= 0, I_D = 1 mA	650			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 650 V			1	µA
		V_{GS} = 0 V, V_{DS} = 650 V; T_C = 125 °C (1)			100	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ±25 V			±5	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	2.25	3	3.75	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 2 A		1.15	1.3	Ω

Notes:

(1)Defined by design, not subject to production test.

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	170	-	pF
C_{oss}	Output capacitance		-	20	-	pF
C_{rss}	Reverse transfer capacitance		-	1	-	pF
$C_{oss\ eq.}$ (1)	Equivalent output capacitance	V_{DS} = 0 to 520 V, V_{GS} = 0 V	-	35	-	pF
R_G	Intrinsic gate resistance	f = 1 MHz, I_D=0 A	-	5	-	Ω
Q_g	Total gate charge	V_{DD} = 350 V, I_D = 1 A, V_{GS}= 10 V, (see *Figure 15: "Test circuit for gate charge behavior"*)	-	5.1	-	nC
Q_{gs}	Gate-source charge		-	0.8	-	nC
Q_{gd}	Gate-drain charge		-	2	-	nC

Notes:

(1)$C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD}= 325 V, I_D = 2 A, R_G = 4.7 Ω, V_{GS} = 10 V (see *Figure 14: "Test circuit for resistive load switching times"* and *Figure 19: "Switching time waveform"*)	-	6.5	-	ns
t_r	Rise time		-	5.9	-	ns
$t_{d(off)}$	Turn-off delay time		-	17.4	-	ns
t_f	Fall time		-	15.2	-	ns

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		4	A
I_{SDM}(1)	Source-drain current (pulsed)		-		16	A
V_{SD}(2)	Forward on voltage	I_{SD} = 4 A, V_{GS} = 0 V	-		1.6	V
t_{rr}	Reverse recovery time	I_{SD} = 4 A, di/dt = 100 A/µs, V_{DD} = 60 V, (see *Figure 19: "Switching time waveform"*)	-	222		ns
Q_{rr}	Reverse recovery charge		-	1.24		µC
I_{RRM}	Reverse recovery current		-	11.2		A
t_{rr}	Reverse recovery time	I_{SD} = 4 A, di/dt = 100 A/µs, V_{DD} = 60 V, T_j = 150 °C (see *Figure 19: "Switching time waveform"*)	-	264		ns
Q_{rr}	Reverse recovery charge		-	1.39		µC
I_{RRM}	Reverse recovery current		-	10.5		A

Notes:

(1)Pulse width limited by safe operating area

(2)Pulsed: pulse duration = 300 µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2: Safe operating area

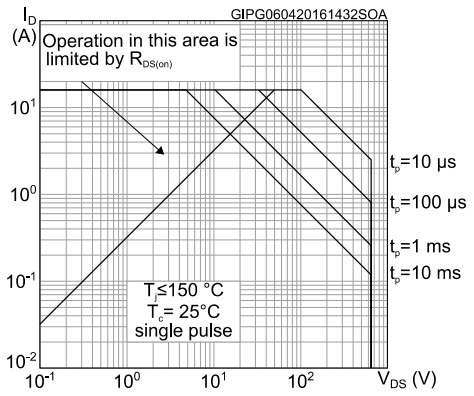


Figure 3: Thermal impedance

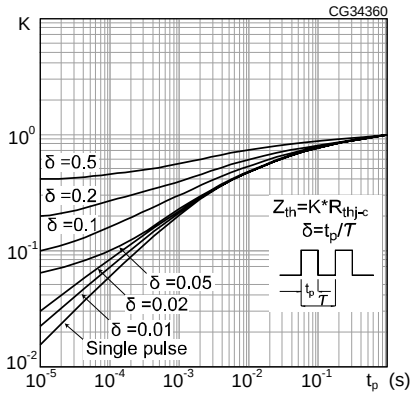


Figure 4: Output characteristics

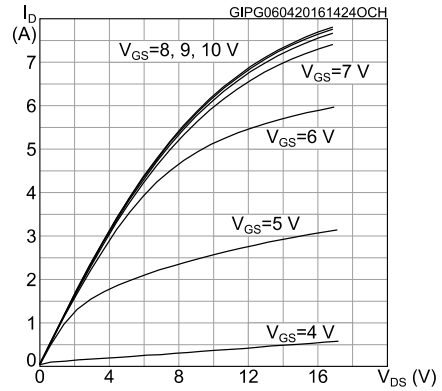


Figure 5: Transfer characteristics

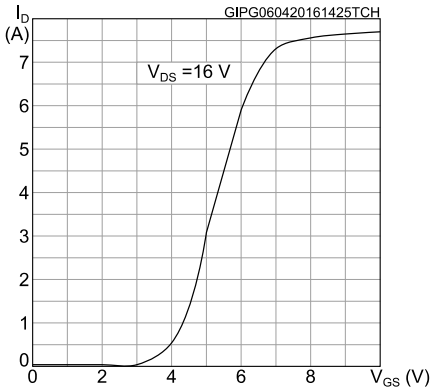


Figure 6: Gate charge vs gate-source voltage

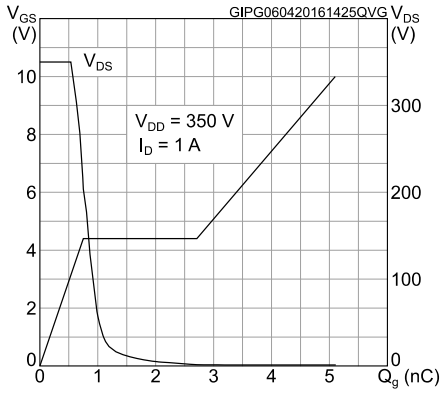


Figure 7: Static drain-source on-resistance

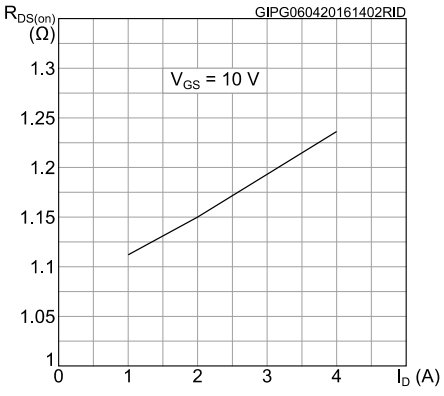


Figure 8: Capacitance variations

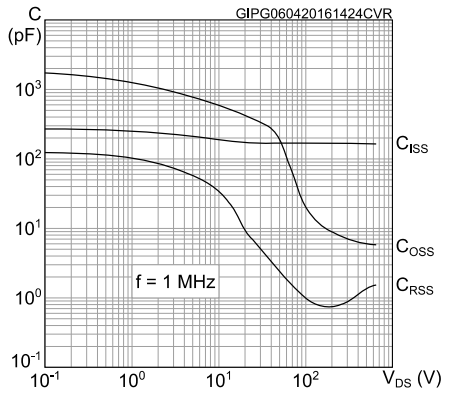


Figure 9: Normalized gate threshold voltage vs temperature

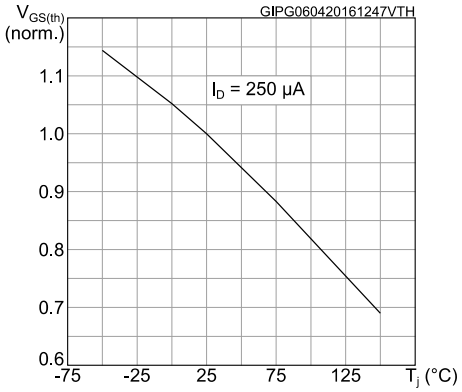


Figure 10: Normalized on-resistance vs temperature

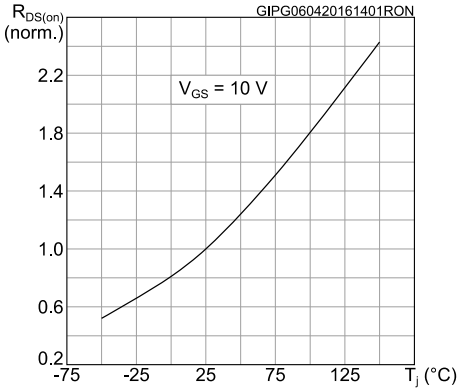


Figure 11: Normalized V(BR)DSS vs temperature

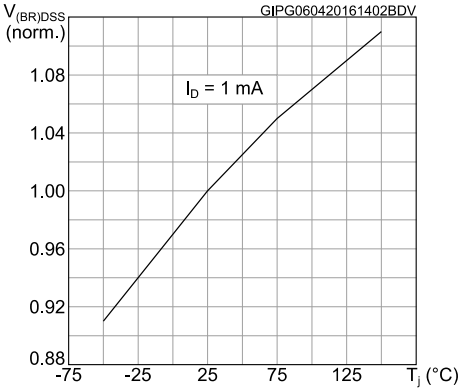


Figure 12: Output capacitance stored energy

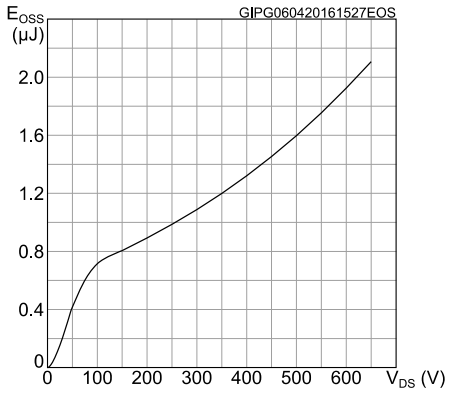
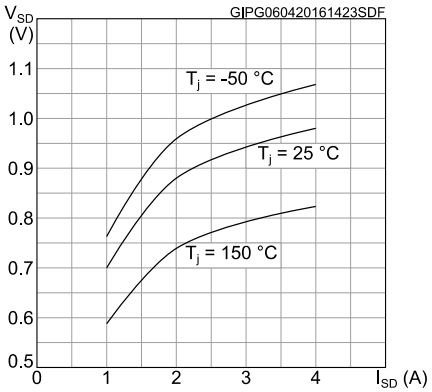


Figure 13: Source-drain diode forward characteristics



3 Test circuits

Figure 14: Test circuit for resistive load switching times

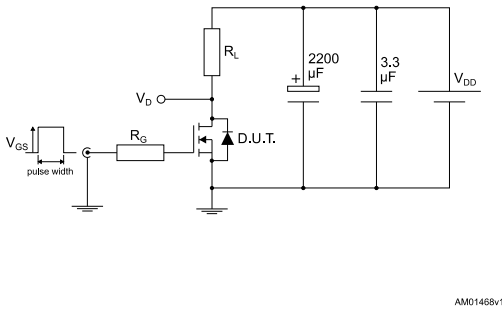


Figure 15: Test circuit for gate charge behavior

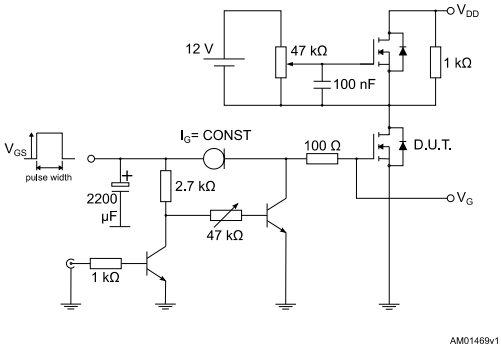


Figure 16: Test circuit for inductive load switching and diode recovery times

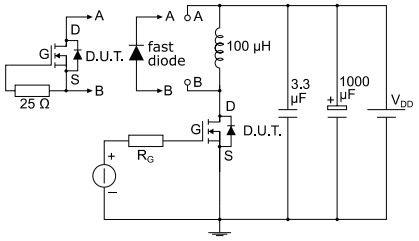


Figure 17: Unclamped inductive load test circuit

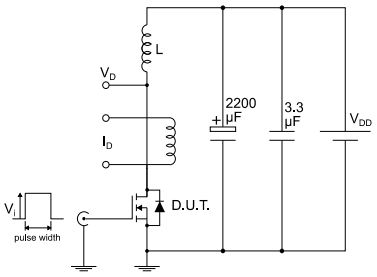


Figure 18: Unclamped inductive waveform

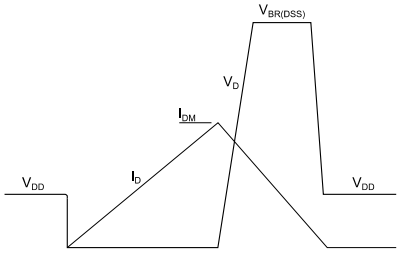
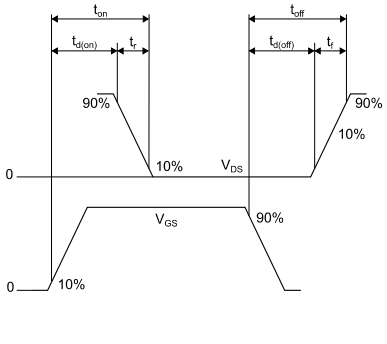


Figure 19: Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: ***www.st.com***. ECOPACK® is an ST trademark.

4.1 IPAK package information

Figure 20: IPAK (TO-251) type A package outline

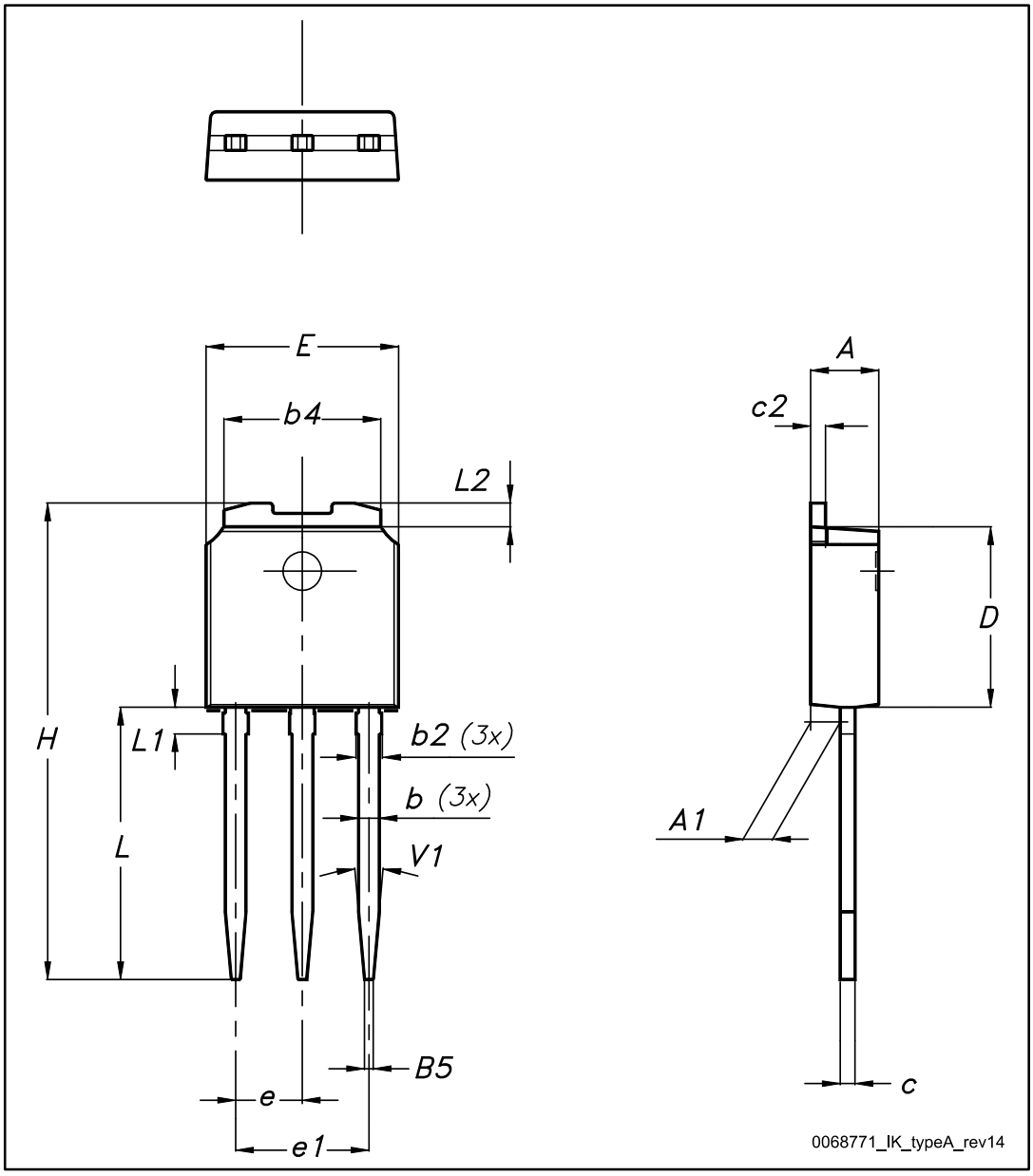


Table 9: IPAK (TO-251) type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
e		2.28	
e1	4.40		4.60
H		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
07-Apr-2016	1	Initial release.
05-May-2016	2	Modified: *Figure 8: "Capacitance variations"* and *Figure 12: "Output capacitance stored energy"* Minor text changes

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